

ISO Certified · 9001 · 17025 · 17043 · 17034

Certificate of Analysis MBH-13X NSC4 G

Nitrogen Stainless Steel (Chill-Cast)

Certified Reference Material

Certified Values listed in wt.% with associated uncertainties

ΑI	0.26 ± 0.01	C	0.470 ± 0.004	Co	0.238 ± 0.003	Cr	31.7 ± 0.2
Cu	0.208 ± 0.007	Mn	7.78 ± 0.06	Мо	1.31 ± 0.02	N	0.90 ± 0.01
Nb	2.37 ± 0.04	Ni	7.52 \pm 0.05	S	0.0065 ± 0.0006	Si	1.53 ± 0.03
V	0.224 ± 0.006	W	0.208 ± 0.005				

Description and Intended Use

This **Certified Reference Material** is covered under the scope of accreditation to **ISO 17034** by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in **ISO 17025** certified laboratories. This CRM may come in the form of a solid disk or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

Instructions for Use

- 1. The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a latthe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface.
- 2. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams.
- 3. The material should be stored in a cool, dry location when not in use.
- 4. Chips are not recommended for gas analysis.

The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Al	С	Co	Cr	Cu	Mn	Мо	N	Nb	Ni	S	Si	٧	W	
1	0.2187	0.4553	0.2306	30.620	0.1843	7.5935	1.2150	0.8715	2.2140	7.4033	0.0043	1.4565	0.2011	0.1900	
2	0.2295	0.4630	0.2309	30.890	0.1890	7.6186	1.2520	0.8718	2.2303	7.4100	0.0056	1.4830	0.2120	0.1954	
3	0.2327	0.4642	0.2310	31.253	0.1892	7.7030	1.2525	0.8927	2.3493	7.4120	0.0056	1.4844	0.2140	0.2030	
4	0.2334	0.4647	0.2343	31.607	0.1973	7.7063	1.3017	0.8970	2.3550	7.4570	0.0060	1.4980	0.2170	0.2047	
5	0.2415	0.4670	0.2350	31.636	0.2011	7.7220	1.3050	0.9000	2.3663	7.4620	0.0063	1.4983	0.2201	0.2050	
6	0.2448	0.4690	0.2360	31.685	0.2040	7.7390	1.3080	0.9096	2.3690	7.4720	0.0063	1.5060	0.2210	0.2060	
7	0.2525	0.4697	0.2369	31.760	0.2073	7.7800	1.3110	0.9143	2.3740	7.4800	0.0063	1.5183	0.2210	0.2078	
8	0.2582	0.4700	0.2373	31.770	0.2090	7.7910	1.3118	0.9169	2.3750	7.4840	0.0064	1.5400	0.2215	0.2083	
9	0.2627	0.4701	0.2380	31.789	0.2101	7.8027	1.3160	0.9170	2.3880	7.4928	0.0065	1.5460	0.2240	0.2090	
10	0.2730	0.4720	0.2385	31.790	0.2118	7.8030	1.3240	0.9200	2.4119	7.5100	0.0070	1.5470	0.2259	0.2137	
11	0.2732	0.4760	0.2399	31.792	0.2123	7.8180	1.3270	0.9433	2.4130	7.5150	0.0071	1.5600	0.2282	0.2141	
12	0.2755	0.4780	0.2401	31.800	0.2205	7.8325	1.3363		2.4210	7.5200	0.0077	1.5830	0.2296	0.2165	
13	0.2842	0.4813	0.2417	31.819	0.2210	7.8380	1.3384		2.4450	7.6343	0.0079	1.5834	0.2357	0.2165	
14	0.2876	0.4830	0.2444	31.897	0.2213	7.8510	1.3395		2.4491	7.6491	0.0092	1.5995	0.2370	0.2228	
15	0.3040		0.2460	31.950	0.2224	7.8785	1.3400			7.6500	0.0064	1.6034	0.2381		
16	0.3130		0.2514	32.438	0.2350	8.0487	1.3889			7.6905	0.0060		0.2410		
17											0.0064				
18															
Mean	0.2615	0.4702	0.2383	31.66	0.2085	7.783	1.310	0.9049	2.369	7.515	0.0065	1.534	0.2242	0.2081	
STDV.	0.0275	0.0075	0.0057	0.425	0.0140	0.107	0.041	0.0213	0.070	0.092	0.0011	0.046	0.0107	0.0086	
Certified	0.26	0.470	0.238	31.7	0.208	7.78	1.31	0.90	2.37	7.52	0.0065	1.53	0.224	0.208	
U_CRM	0.01	0.004	0.003	0.2	0.007	0.06	0.02	0.01	0.04	0.05	0.0006	0.03	0.006	0.005	
Methods	I,W,A	С	I,W,A	I,W	I,W,A	I,W,A	I	F	I,W,A	I,W,A	C,I	I,W	I,W,A	I,W,A	

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

Certification Laboratories

Element - Teeside
Sheffield Analytical Services
AMG Superalloys UK Ltd
Mineral & Metallurgical Laboratories
Instytut Metallurgii Zelaza
Luo Yang Copper Co
Raghavendra SpectroMet Laboratory
Anchorcert Analytical
Analyticka Laborator Lithea sro

Middlesbrough, England Sheffield, England Rotherham, England Bangalore, India Gliwice, Poland Luo Yang, He Nan, China Bangalore, India Birmingham, England Brno, Czech Republic

TUV Nord-Czech
Metals Technology (Testing) Ltd
Laboratory Testing, Inc
Tec-Eurolab
Universal Scientific Laboratory Pty Ltd
Genitest Inc
TCR Engineering Services Ltd

Shanghai Jinyi Test Tech Co

Scrooby's Analytical Services

Brno, Czech Republic Sheffield, England Hatfield, PA Campogalliano, Italy Sydney, Australia Montreal, Canada Mumbai, India Shanghai, China Benoni, South Africa

Much of the analytical work performed to assess this material has been carried out by laboratories with proven competence, as indicated by their accreditation to ISO 17025. It is an implicit requirement for this accreditation that analytical work should be performed with due traceability, via an unbroken chain of comparisons, each with stated uncertainty, to primary standards such as the mole, or to nationally- or internationally-recognised reference materials. Of the individual results herein, some have traceability (to the mole) via primary analytical methods. Some are traceable to substances of known stoichiometry. Most have traceability via commercial solutions. Furthermore, some results have additional traceability to NIST standards, as part of the analytical calibration or process control.

Homogeneity and Uncertainty

"Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculated uncertainty due to inhomogeneity (U_{hom}). Uncertainty of the material is calculated by equation 2, where $H=U_{hom}$, S= Standard deviation, t= t-value at 95% CI, and t= number of observations.

1.
$$N_{min} = \max(10, \sqrt[3]{N_{prod}})$$
 2. $U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$

Expiration

The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Kimberly Halkiotis, Global Product Manager

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